

<b>Search Notes</b> 		Application/Control No.	Applicant(s)/Patent under Reexamination
		10/643,599	HEINONEN ET AL.
		Examiner	Art Unit
		David Mis	2817

SEARCHED			
Class	Subclass	Date	Examiner
331	2, 16, 18, 25, 49	1/26/2005	DM
327	147-150		
332	127		
360	51		
375	376		
455	260		
UPATED 5/25/05 DM			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
AS ABOVE	375	5/25	DM